

<b>Notice of References Cited</b>	Application/Control No. 10/807,432		Applicant(s)/Patent Under Reexamination YOSHIDA ET AL.	
	Examiner Nam Huynh		Art Unit 2617	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0065774	05-2002	Young et al.	705/41
*	B	US-2001/0037245	11-2001	Ranganath et al.	705/16
*	C	US-2003/0229590	12-2003	Byrne et al.	705/40
*	D	US-2003/0163416	08-2003	Kitajima, Hironobu	705/39
*	E	US-2005/0177437	08-2005	Ferrier, Jonathan	705/026
*	F	US-2002/0026367	02-2002	Villaret et al.	705/17
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.